

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s) : **Chi-Kuang Sun and Shi-Wei Chu**  
Date: September 9, 2003  
Serial No. :  
Group Art Unit:  
Filed :  
For : **Harmonic Generation Microscopy**

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Honorable Commissioner of Patents  
and Trademarks  
Washington, D.C. 20231


INFORMATION DISCLOSURE STATEMENT

Sir:

Attached is a completed Form PTO-1449 and copies of the pertinent parts of the references cited thereon. Comments on any non-English-language references (if any) pursuant to Rule are submitted herewith.

Respectfully submitted

Applicants(s):

 Shi-Wei Chu

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Encl: PTO-1449 & References

|   |    |  |            |                                   |       |            |                               |
|---|----|--|------------|-----------------------------------|-------|------------|-------------------------------|
| FORM PTO-1449 (Substitute)  |    |  |            | ATTY. DOCKET NO.<br>03198-URS     |       | SERIAL NO. |                               |
| LIST OF PRIOR ART CITED BY APPLICANT<br>(Use several sheets if necessary)   |    |  |            | APPLICANT<br>Chi-Kuang SUN et al. |       |            |                               |
|   |    |  |            | FILING DATE                       |       | GROUP      |                               |
| U.S. PATENT DOCUMENTS   |    |  |            |                                   |       |            |                               |
| *EXAMINER<br>INITIAL  |    | DOCUMENT NUMBER  | DATE       | NAME                              | CLASS | SUBCLASS   | FILING DATE IF<br>APPROPRIATE |
|   | AA | 5,828,459  | 10/27/1998 | Silberberg                        | 356   | 444        | 4/28/1997                     |
|   | AB | 6,208,886  | 3/27/2001  | Alfano et al.                     | 600   | 473        | 4/3/1998                      |
|   | AC |  |            |                                   |       |            |                               |
|   | AD |  |            |                                   |       |            |                               |
|   | AE |  |            |                                   |       |            |                               |
|   | AF |  |            |                                   |       |            |                               |
|   | AG |  |            |                                   |       |            |                               |
|   | AH |  |            |                                   |       |            |                               |
|   | AI |  |            |                                   |       |            |                               |
|   | AJ |  |            |                                   |       |            |                               |
|   | AK |  |            |                                   |       |            |                               |
| FOREIGN PATENT DOCUMENTS  |    |  |            |                                   |       |            |                               |
|   | AL |  |            |                                   |       |            |                               |
|   | AM |  |            |                                   |       |            |                               |
|   | AN |  |            |                                   |       |            |                               |
|   | AO |  |            |                                   |       |            |                               |
|   | AP |  |            |                                   |       |            |                               |
| OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)  |    |  |            |                                   |       |            |                               |
|   | AQ | Two-Photon Laser Scanning fluorescence Microscopy<br>Winfried Denk, James H. Strickler and Watt W. Webb, Science, New Series, Volume 248, Issue 4951<br>(April 6, 1990), pp 73-76  |            |                                   |       |            |                               |
|   | AR | Second-harmonic imaging in the scanning optical microscope<br>J. N. Gannaway and C. J. R. Sheppard, Optic Quantum Electron, 1978, Volume 10, pp. 435-439                           |            |                                   |       |            |                               |
|   | AS | Nonlinear scanning laser microscopy by third harmonic generation<br>Y. Barad, H. Eisenberg, M. Horowitz and Y. Silberberg, Applied Physics Letters, 1997, Volume 70, pp<br>922-924 |            |                                   |       |            |                               |
| EXAMINER  |    |  |            | DATE CONSIDERED                   |       |            |                               |
| *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. |    |  |            |                                   |       |            |                               |